

WFP840B-VB Datasheet

N-Channel 500V (D-S)Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	500				
R _{DS(on)} (Ω)	V _{GS} = 10 V 0.660				
Q _g (Max.) (nC)	81				
Q _{gs} (nC)	20				
Q _{gd} (nC)	36				
Configuration	Single	e			

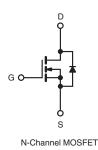
FEATURES

• Lower Gate Charge Q_q Results in Simpler Drive Regirements



- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage
- Compliant to RoHS Directive 2002/95/EC





ABSOLUTE MAXIMUM RATINGS ($T_{\rm C}$	= 25 °C, unl	ess otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	500	v	
Gate-Source Voltage			V _{GS}	± 20		
Continuous Drain Current	V at 10 V	T _C = 25 °C	I	13		
	V _{GS} at 10 V	T _C = 100 °C	I _D	8.1	А	
Pulsed Drain Current ^a			I _{DM}	50		
Linear Derating Factor				2.0	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	560	mJ	
Avalanche Current ^a			I _{AR}	13	А	
Repetitive Avalanche Energy ^a			E _{AR}	25	mJ	
Maximum Power Dissipation $T_{C} = 25 \text{ °C}$			PD	250	W	
Peak Diode Recovery dV/dt ^c			dV/dt	9.2	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature) for 10 s			300 ^d			
Mounting Torque	6-32 or M3 screw			10	lbf ∙ in	
Mounting Torque				1.1	N · m	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Starting T_J = 25 °C, L = 5.7 mH, R_g = 25 Ω , I_{AS} =14 A, dV/dt = 7.6 V/ns (see fig. 12a). c. I_{SD} ≤ 14 A, dI/dt ≤ 250 A/µs, V_{DD} ≤ V_{DS}, T_J ≤ 150 °C.

d. 1.6 mm from case.

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THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	62	
Case-to-Sink, Flat, Greasd Surface	R _{thCS}	0.50	-	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.50	

SPECIFICATIONS ($T_J = 25 \text{ °C}$, u					1	1	r –
PARAMETER	SYMBOL	TES	T CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static		1				1	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	= 0 V, I _D = 250 μA	500	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	se to 25 °C, $I_D = 1 \text{ mA}$	-	0.55	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μΑ	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		$V_{GS} = \pm 20V$	-	-	±100	nA
Zara Cata Valtaga Drain Current		V _{DS} =	$V_{DS} = 500 \text{ V}, V_{GS} = 0 \text{ V}$		-	25	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 400 \	/, V _{GS} = 0 V, T _J = 125 °C	-	-	250	μA
Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 10 \text{ V}$	$I_D = 8.4 \text{ A}^{b}$	-	0.660	-	Ω
Forward Transconductance	g fs	V _{DS}	= 50 V, I _D = 8.4 A	8.1	-	-	S
Dynamic					•		
Input Capacitance	C _{iss}		$V_{GS} = 0 V$,	-	1910	-	
Output Capacitance	C _{oss}		$V_{GS} = 0 V,$ $V_{DS} = 25 V,$ f = 1.0 MHz, see fig. 5		290	-	1
Reverse Transfer Capacitance	C _{rss}	f = 1			11	-	1_
		V _{GS} = 0 V	V _{DS} = 1.0 V, f = 1.0 MHz	-	2730	-	pF
Output Capacitance	C _{oss}		V _{DS} = 400 V, f = 1.0 MHz	-	82	-	
Effective Output Capacitance	C _{oss} eff.		V _{DS} = 0 V to 400 V ^c	-	160	-	
Total Gate Charge	Qg			-	-	81	
Gate-Source Charge	Q _{gs}	-	$I_D = 14 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13^{b}	-	-	20	nC
Gate-Drain Charge	Q _{gd}	-	see lig. o and 10	-	-	36	
Turn-On Delay Time	t _{d(on)}	V _{GS} = 10 V		-	15	-	
Rise Time	t _r	-	$V_{DD} = 250 \text{ V}, \text{ I}_{D} = 14 \text{ A},$	-	39	-	
Turn-Off Delay Time	t _{d(off)}	-	$R_g = 7.5 \Omega$, see fig. 10 ^b	-	39	-	- ns
Fall Time	t _f	-	5	-	31	-	
Drain-Source Body Diode Characteristic	s	1			1	I	
Continuous Source-Drain Diode Current	I _S	MOSFET sym showing the	MOSFET symbol		-	13	
Pulsed Diode Forward Current ^a	I _{SM}	integral revers p - n junction		-	-	56	A
Body Diode Voltage	V_{SD}	T _J = 25 °C	C, I _S = 14 A, V _{GS} = 0 V ^b	-	-	1.5	V
Body Diode Reverse Recovery Time	t _{rr}			-	370	550	ns
Body Diode Reverse Recovery Charge	Q _{rr}	T _J =	25 °C, I _F = 14 A, °C, dl/dt = 100 A/µs ^b	-	4.4	6.5	μC
Body Diode Reverse Recovery Current	I _{RRM}	- ij = i20	$0, u/u = 100 A/\mu S^2$	-	21	31	Α
Forward Turn-On Time	t _{on}	Intrinsic tu	rn-on time is negligible (turn	-on is do	minated b	v Ls and	Ln)

Notes

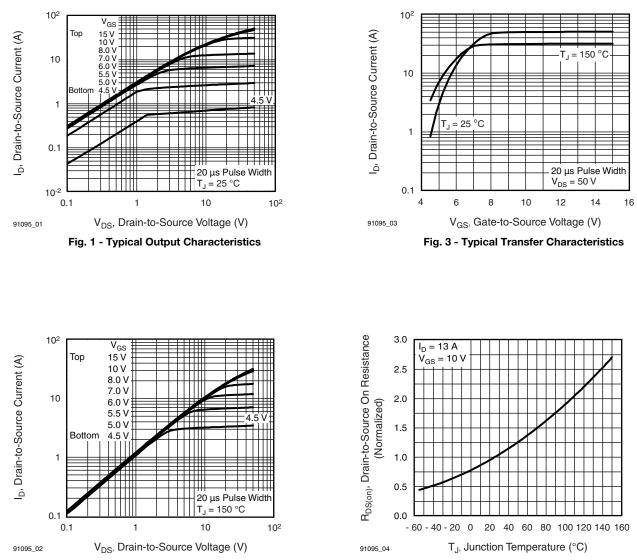
a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width \leq 300 µs; duty cycle \leq 2 %.

c. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .

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TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



Fig. 4 - Normalized On-Resistance vs. Temperature



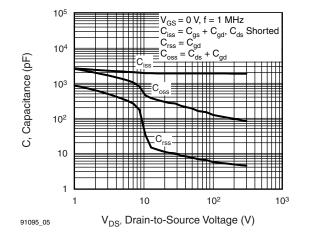


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

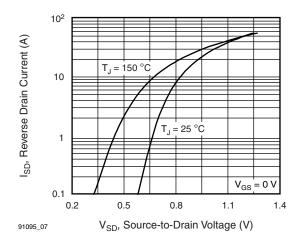


Fig. 7 - Typical Source-Drain Diode Forward Voltage

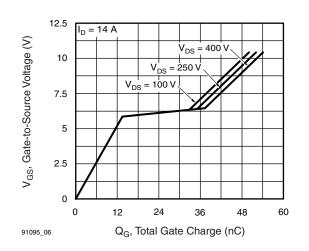


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

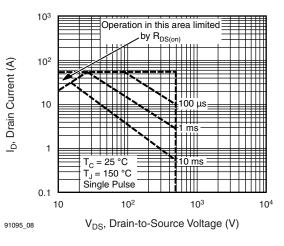


Fig. 8 - Maximum Safe Operating Area

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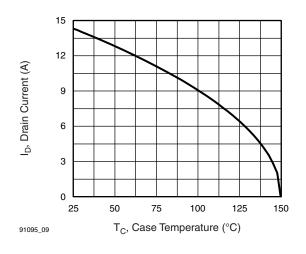


Fig. 9 - Maximum Drain Current vs. Case Temperature

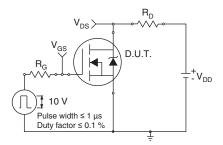


Fig. 10a - Switching Time Test Circuit

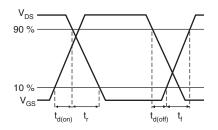


Fig. 10b - Switching Time Waveforms

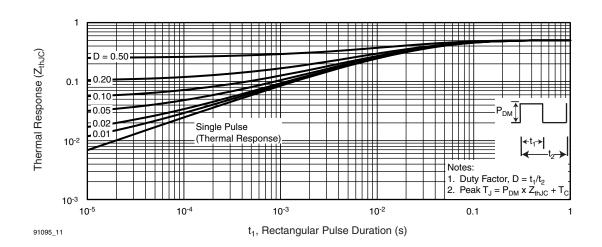


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



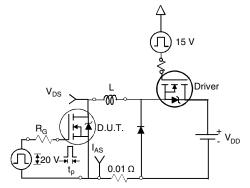


Fig. 12a - Unclamped Inductive Test Circuit

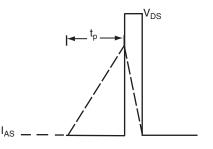


Fig. 12b - Unclamped Inductive Waveforms

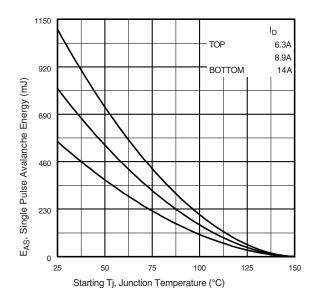
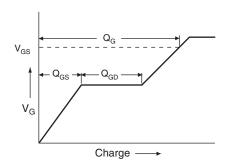


Fig. 12c - Maximum Avalanche Energy vs. Drain Current





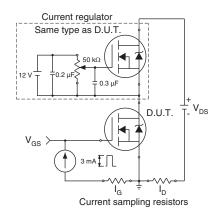
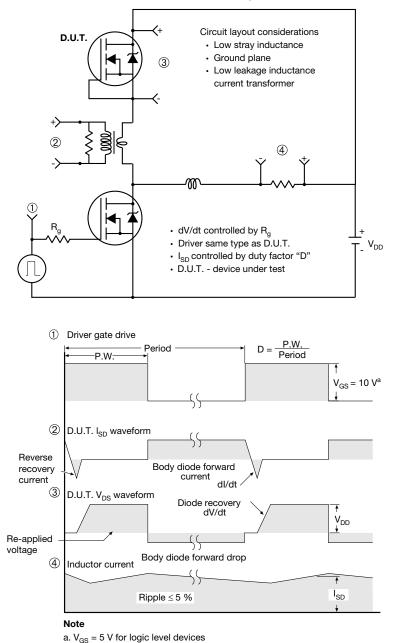


Fig. 13b - Gate Charge Test Circuit





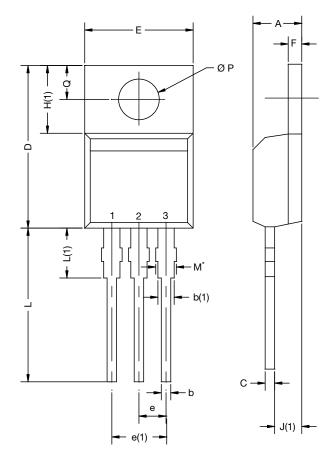
Peak Diode Recovery dV/dt Test Circuit

Fig. 14 - For N-Channel

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TO-220AB



DIM	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.24	4.65	0.167	0.183	
b	0.69	1.02	0.027	0.040	
b(1)	1.14	1.78	0.045	0.070	
С	0.36	0.61	0.014	0.024	
D	14.33	15.85	0.564	0.624	
Е	9.96	10.52	0.392	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.10	6.71	0.240	0.264	
J(1)	2.41	2.92	0.095	0.115	
L	13.36	14.40	0.526	0.567	
L(1)	3.33	4.04	0.131	0.159	
ØР	3.53	3.94	0.139	0.155	
Q	2.54	3.00	0.100	0.118	
ECN: X15- DWG: 603	0364-Rev. C, 1	14-Dec-15			

Note

- M^{\star} = 0.052 inches to 0.064 inches (dimension including protrusion), heatsink hole for HVM



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